## Search Notes



Class

Application/Control	N	lc	כ
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10539239

Applicant(s)/Patent Under Reexamination

IWAUCHI ET AL.

Examiner

Art Unit

Makiya, David J

2885

## **SEARCHED**

Class	Subclass	Date	Examiner
362	629	2/23/2007	DJM
362	629	8/28/2007	DJM

SEAF	RCH	NO	<b>TES</b>
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Search Notes	Date	Examiner
Search in EAST attached	2/23/2007	DJM
362/600-634	2/23/2007	DJM .
Updated search in EAST attached		

INTERFERENCE SEARCH	INTERFERENCE SEARCH		
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